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Sheet 1 of 1

Complete if Known	
Application Number	09/894,125
Filing Date	June 29, 2001
First Named Inventor	Shunpei YAMAZAKI et al.
Group Art Unit	2823
Examiner Name	B. Kebede
Attorney Docket Number	0756-2330

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.[1]	Foreign Patent Document: Office[2]	Number[3]	Kind Code[4] (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T[5]
BK		JP	07-130652			05/19/1995		AB

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.[1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T[5]
BK		R. Shimokawa et al., *Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement*, Japanese Journal of Applied Physics, Volume 27, No. 5, May, 1988, pp. 751-758	
BK		H. Furue et al., *P-78: Characteristics and Driving Scheme of Polymer-Stabilized Monostable FLCD Exhibiting Fast Response Time and High Contrast Ratio with Gray-Scale Capability*, SID, 1998, pp. 782-785.	
BK		T. Yoshida, *33.2: A Full-Color Thresholdless Antiferroelectric LCD Exhibiting Wide Viewing Angle with Fast Response Time*, SID Digest, 1997, pp. 841-844.	
BK		H. Dorin, et al., *Chemistry the Study of Matter*, Prentice Hall, Fourth Edition, 1992, p. 532.	
BK		Y. Aya, et al., *Improvement of SPC Poly-Si Film Using the ELA Method*, 1997 International Workshop on Active-Matrix Liquid-Crystal Displays, September 11-12, 1997, pp. 167-170.	
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BK		S. Inui, et al., *Thresholdless Antiferroelectricity in Liquid Crystals and its Application Displays*, J. Mater. Chem., 1996, pp. 671-673	

Examiner Signature	Bkebede	Date Considered	12/10/2004

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